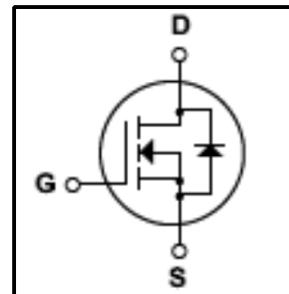
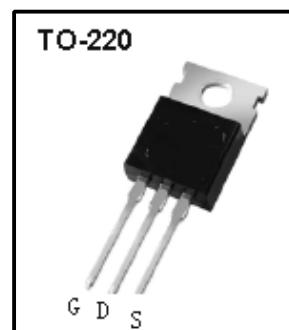


Silicon N-Channel MOSFET
Features

- 12A,650V,RDS(on)(Max0.78Ω)@VGS=10V
- Ultra-low Gate Charge(Typical 30nC)
- Fast Switching Capability
- 100% Avalanche Tested
- Maximum Junction Temperature Range(150°C)


General Description

This Power MOSFET is produced using Winsemi's advanced planar stripe, VDMOS technology. This latest technology has been especially designed to minimize on-state resistance, have a high rugged avalanche characteristics. This devices is specially well suited for AC-DC switching power supplies, DC-DC power converters, high voltage H-bridge motor drive PMW


Absolute Maximum Ratings

Symbol	Parameter	Value	Units
V_{DSS}	Drain Source Voltage	650	V
I_D	Continuous Drain Current(@ $T_c=25^\circ\text{C}$)	12	A
	Continuous Drain Current(@ $T_c=100^\circ\text{C}$)		A
I_{DM}	Drain Current Pulsed (Note1)		A
V_{GS}	Gate to Source Voltage	± 30	V
E_{AS}	Single Pulsed Avalanche Energy (Note 2)	990	mJ
E_{AR}	Repetitive Avalanche Energy (Note 1)	22	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)	4.5	V/ns
P_D	Total Power Dissipation(@ $T_c=25^\circ\text{C}$)	178	W
	Derating Factor above 25°C	1.43	W/°C
T_J, T_{stg}	Junction and Storage Temperature	-55~150	°C
T_L	Channel Temperature	300	°C

Thermal Characteristics

Symbol	Parameter	Value			Units
		Min	Typ	Max	
R_{QJC}	Thermal Resistance, Junction-to-Case	-	-	0.70	°C
R_{QCS}	Thermal Resistance, Case-to-Sink	-	-	-	°C
R_{QJA}	Thermal Resistance, Junction-to-Ambient	-	-	62.5	W
					W
					W

Electrical Characteristics ($T_c = 25^\circ\text{C}$)

Characteristics	Symbol	Test Condition	Min	Type	Max	Unit
Gate leakage current	I_{GSS}	$V_{GS} = \pm 30 \text{ V}, V_{DS} = 0 \text{ V}$	-	-	± 100	nA
Gate-source breakdown voltage	$V_{(BR)GSS}$	$I_G = \pm 10 \mu\text{A}, V_{DS} = 0 \text{ V}$	± 30	-	-	V
Drain cut-off current	I_{DSS}	$V_{DS} = 650 \text{ V}, V_{GS} = 0 \text{ V}$	-	-	10	μA
		$V_{DS} = 480 \text{ V}, T_c = 125^\circ\text{C}$	-	-	100	μA
Drain-source breakdown voltage	$V_{(BR)DSS}$	$I_D = 250 \mu\text{A}, V_{GS} = 0 \text{ V}$	650	-	-	V
Gate threshold voltage	$V_{GS(\text{th})}$	$V_{DS} = 10 \text{ V}, I_D = 250 \mu\text{A}$	3	-	4.5	V
Drain-source ON resistance	$R_{DS(\text{ON})}$	$V_{GS} = 10 \text{ V}, I_D = 6\text{A}$	-	0.64	0.78	Ω
Forward Transconductance	g_{fs}	$V_{DS} = 50 \text{ V}, I_D = 6\text{A}$	-	6.4	-	s
Input capacitance	C_{iss}	$V_{DS} = 25 \text{ V},$ $V_{GS} = 0 \text{ V},$ $f = 1 \text{ MHz}$	-	1830	-	pF
Reverse transfer capacitance	C_{rss}		-	155	-	
Output capacitance	C_{oss}		-	2.0	-	
Switching time	Rise time	t_r	$V_{DD} = 325 \text{ V},$ $I_D = 12 \text{ A}$ $R_G = 25 \Omega$ (Note 4,5)	-	50	ns
	Turn-on time	t_{on}		-	49	
	Fall time	t_f		-	310	
	Turn-off time	t_{off}		-	54	
Total gate charge (gate-source plus gate-drain)	Q_g	$V_{DD} = 520 \text{ V},$ $V_{GS} = 10 \text{ V},$ $I_D = 12 \text{ A}$ (Note 4,5)	-	51.7	-	nC
Gate-source charge	Q_{gs}		-	9.6	-	
Gate-drain ("miller") Charge	Q_{gd}		-	18.6	-	

Source-Drain Ratings and Characteristics ($T_a = 25^\circ\text{C}$)

Characteristics	Symbol	Test Condition	Min	Type	Max	Unit
Continuous drain reverse current	I_{DR}	-	-	-	12	A
Pulse drain reverse current	I_{DRP}	-	-	-	48	A
Forward voltage (diode)	V_{DSF}	$IDR = 10 \text{ A}, V_{GS} = 0 \text{ V}$	-	-	1.4	V
Reverse recovery time	t_{rr}	$IDR = 10 \text{ A}, V_{GS} = 0 \text{ V},$ $dIDR / dt = 100 \text{ A} / \mu\text{s}$	-	450	-	ns
Reverse recovery charge	Q_{rr}		-	5.0	-	μC

Note 1. Repeatability rating :pulse width limited by junction temperature
 2. $L=14\text{mH}, I_{AS}=12\text{A}, V_{DD}=95\text{V}, R_G=25\Omega$, Starting $T_J=25^\circ\text{C}$
 3. $I_{SD}\leq 10\text{A}, dI/dt\leq 200\text{A}/\mu\text{s}, V_{DD}<BV_{DSS}$, STARTING $TJ=25^\circ\text{C}$
 4.Pulse Test: Pulse Width $\leq 300\text{us}$, Duty Cycles $\leq 2\%$
 5.Essentially independent of operating temperature.

This transistor is an electrostatic sensitive device

Please handle with caution

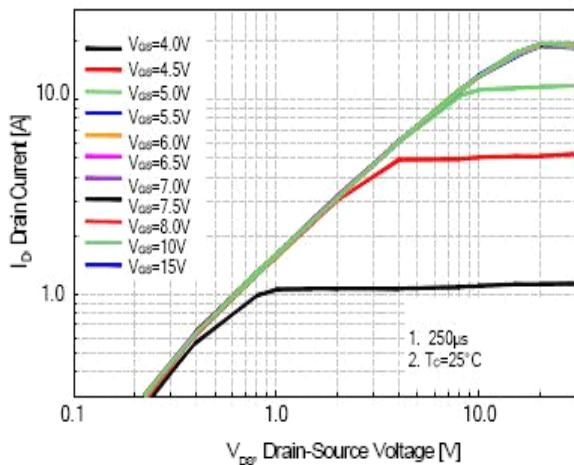


Fig. 1 On-State Characteristics

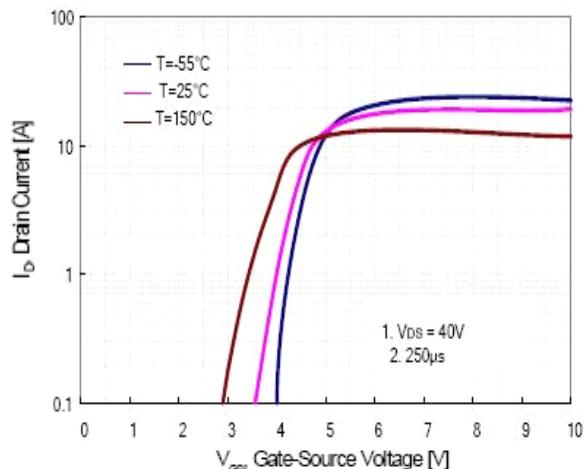


Fig. 2 Transfer Current Characteristics

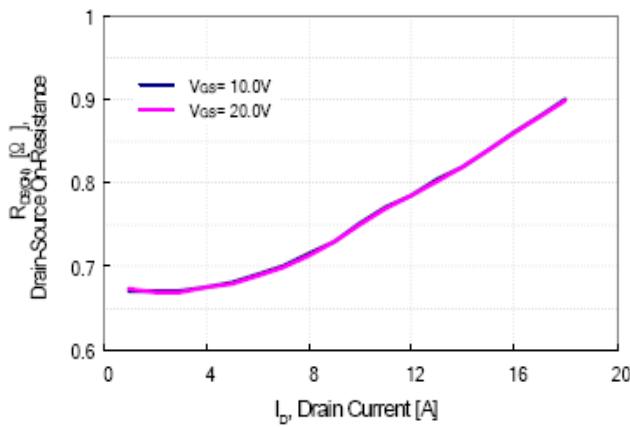


Fig. 3 On-Resistance Variation vs Drain Current

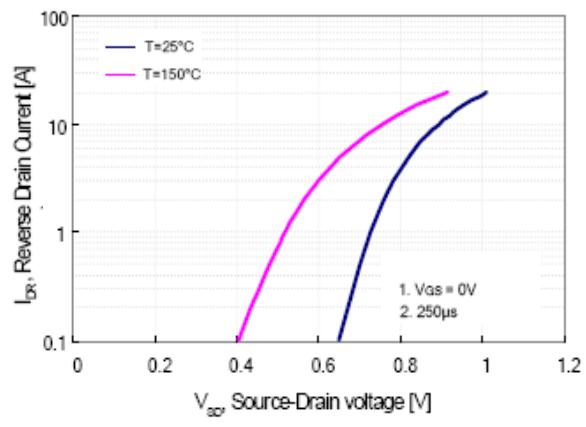


Fig. 4 Body Diode Forward Voltage Variation with Source Current And Temperature

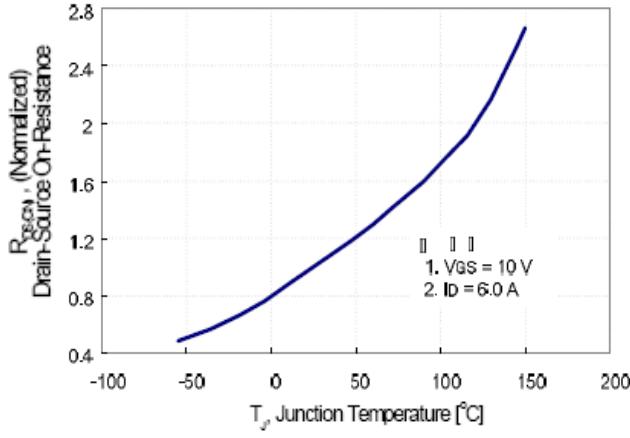


Fig. 5 On-Resistance Variation vs Junction Temperature

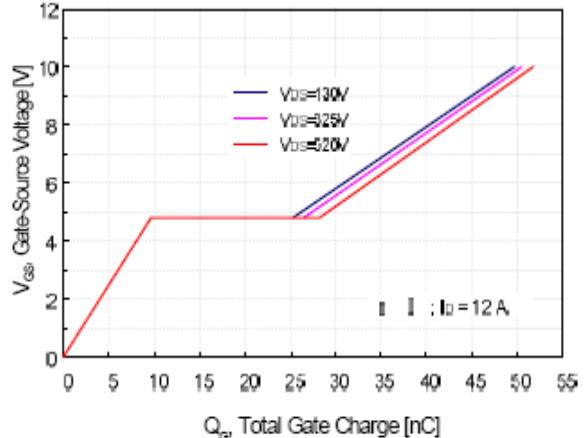


Fig. 6 Gate Charge Characteristics

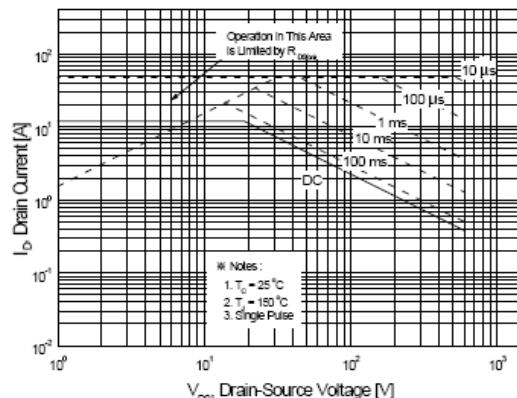


Fig.7 Maximum Safe Operation Area

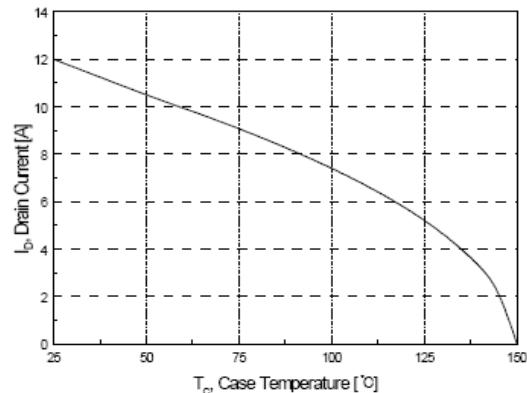


Fig.8 Maximum Drain Current vs Case Temperature

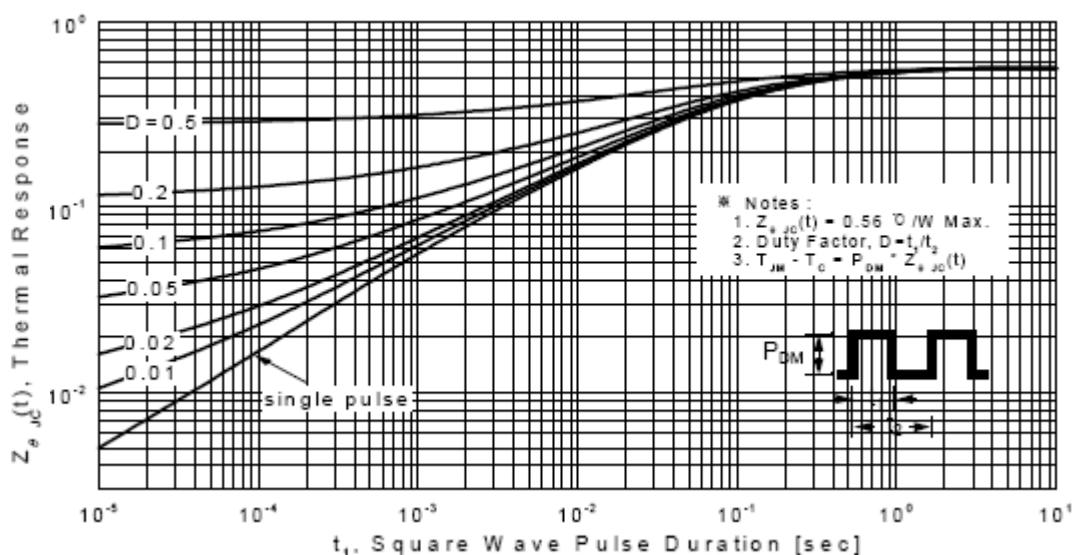


Fig.9 Transient Thermal Response Curve

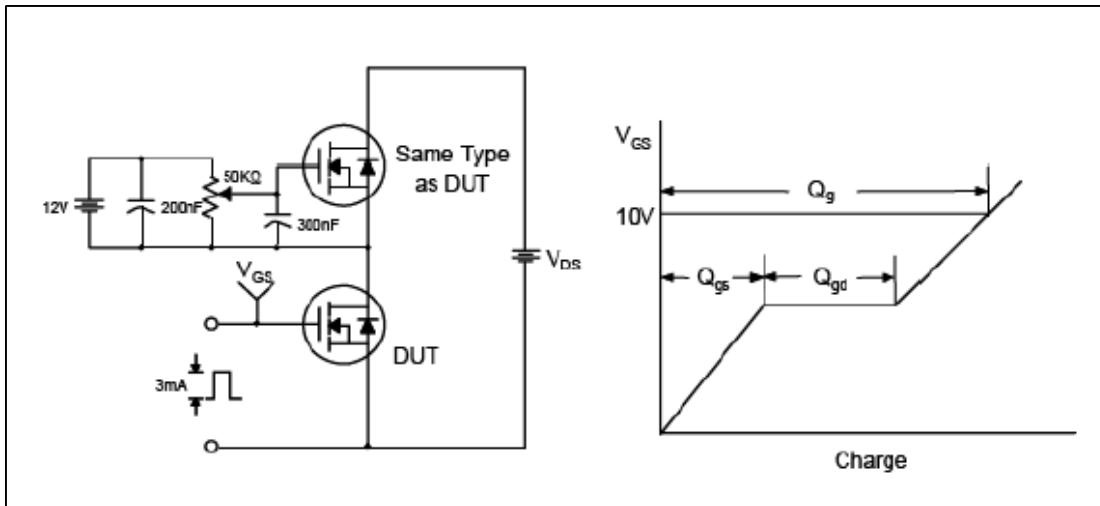


Fig.10 Gate Test circuit & Waveform

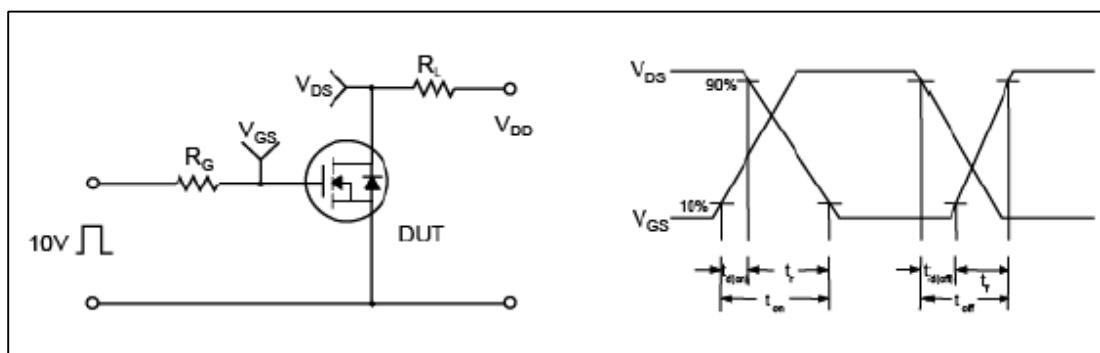


Fig.11 Resistive Switching Test Circuit & Waveform

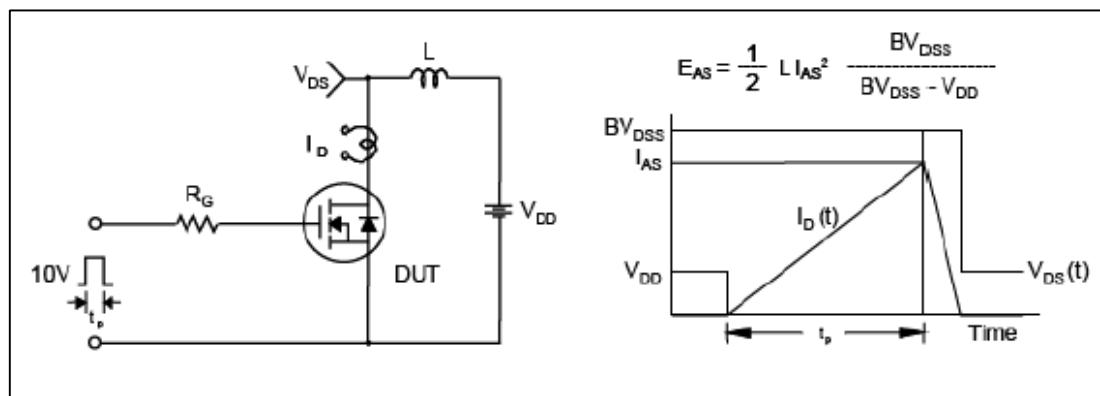


Fig.12 Uncamped Inductive Switching Test Circuit & Waveform

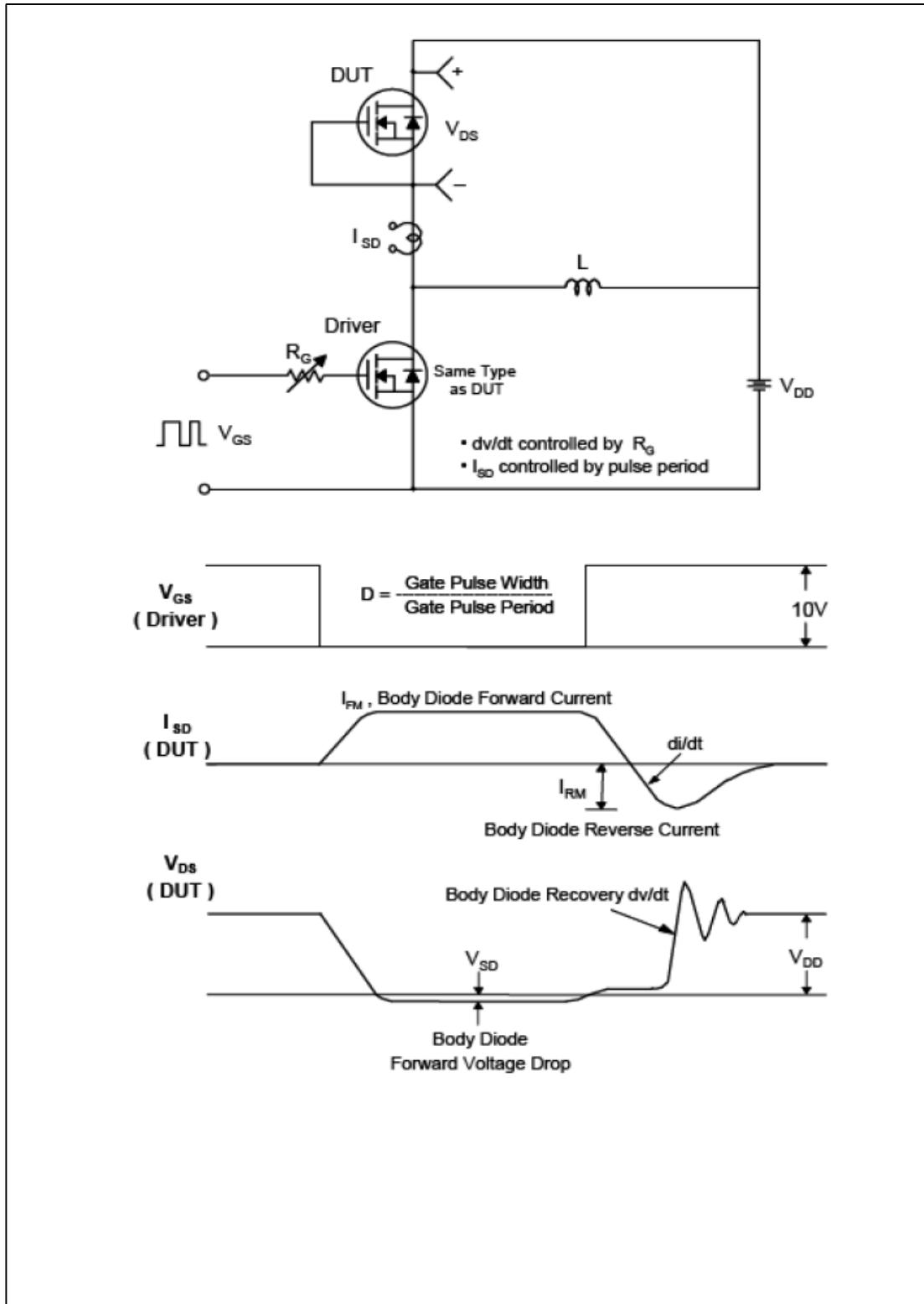


Fig.13 Peak Diode Recovery dv/dt Test Circuit & Waveform

TO-220 Package Dimension

